

Notice of References CitedApplicant/Patent
PRATER et al.Application/Control No.
08/871,029Examiner
Daniel LarkinArt Unit
2856

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U.S. PATENT DOCUMENTS

	Document Number Country Code-Number-Kind Code	Date MM-YYYY ¹	Name	Classification ²	
A	5,172,002	12/1992	Marshall	250	306
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NON-PATENT DOCUMENTS

	Include, as applicable: Author, Title, Date, Publisher, Edition or Volume, Pertinent Pages
U	Jung et al., "Novel Stationary-Sample Atomic Force Microscope With Beam-Tracking Lens", Electronic Letters, 04 February 1993, Vol. 29, No. 3, pp. 264-266.
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